





6-Pin DIP Zero-Cross Optoisolators Triac Driver Output (800 Volts Peak)

The MOC3081, MOC3082 and MOC3083 devices consist of gallium arsenide infrared emitting diodes optically coupled to monolithic silicon detectors performing the function of Zero Voltage Crossing bilateral triac drivers.

They are designed for use with a triac in the interface of logic systems to equipment powered from 240 Vac lines, such as solid–state relays, industrial controls, motors, solenoids and consumer appliances, etc.

- Simplifies Logic Control of 240 Vac Power
- · Zero Voltage Crossing
- dv/dt of 1500 V/μs Typical, 600 V/μs Guaranteed
- To order devices that are tested and marked per VDE 0884 requirements, the suffix "V" must be included at end of part number. VDE 0884 is a test option.

Recommended for 240 Vac(rms) Applications:

- Solenoid/Valve Controls
- Lighting Controls
- Static Power Switches
- AC Motor Drives

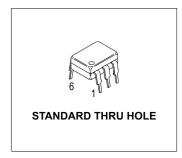
- Temperature Controls
- E.M. Contactors
- AC Motor Starters
- Solid State Relays

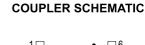
MAXIMUM RATINGS

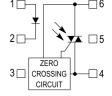
Rating	Symbol	Value	Unit	
INPUT LED				
Reverse Voltage	VR	6	Volts	
Forward Current — Continuous	lF	60	mA	
Total Power Dissipation @ T _A = 25°C Negligible Power in Output Driver	PD	120	mW	
Derate above 25°C		1.41	mW/°C	
OUTPUT DRIVER				
Off–State Output Terminal Voltage	VDRM	800	Volts	
Peak Repetitive Surge Current (PW = 100 μs, 120 pps)	ITSM	1	А	
Total Power Dissipation @ T _A = 25°C Derate above 25°C	PD	150 1.76	mW mW/°C	
TOTAL DEVICE				
Isolation Surge Voltage ⁽¹⁾ (Peak ac Voltage, 60 Hz, 1 Second Duration)	VISO	7500	Vac(pk)	
Total Power Dissipation @ T _A = 25°C Derate above 25°C	P _D	250 2.94	mW mW/°C	
Junction Temperature Range	TJ	-40 to +100	°C	
Ambient Operating Temperature Range	TA	-40 to +85	°C	
Storage Temperature Rang	T _{stg}	-40 to +150	°C	
Soldering Temperature (10 s)	TL	260	°C	

^{1.} Isolation surge voltage, V_{ISO}, is an internal device dielectric breakdown rating. For this test, Pins 1 and 2 are common, and Pins 4, 5 and 6 are common.

MOC3081 MOC3082 MOC3083







- 1. ANODE
- 2. CATHODE
- 3. NC
- 4. MAIN TERMINAL
- 5. SUBSTRATE DO NOT CONNECT
- 6. MAIN TERMINAL

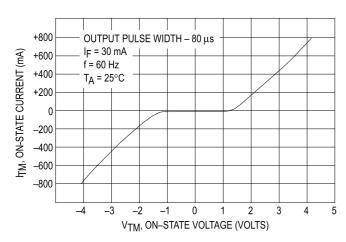


ELECTRICAL CHARACTERISTICS (T_A = 25°C unless otherwise noted)

Characteristic	Symbol	Min	Тур	Max	Unit
INPUT LED	•	•	•		•
Reverse Leakage Current (V _R = 6 V)	I _R	_	0.05	100	μΑ
Forward Voltage (I _F = 30 mA)	VF	_	1.3	1.5	Volts
OUTPUT DETECTOR (I _F = 0)					•
Leakage with LED Off, Either Direction (V _{DRM} = 800 V ⁽¹⁾)	IDRM1	_	80	500	nA
Critical Rate of Rise of Off–State Voltage(3)	dv/dt	600	1500	_	V/μs
COUPLED	•	•	•		•
LED Trigger Current, Current Required to Latch Output (Main Terminal Voltage = 3 V ⁽²⁾) MOC3081 MOC3082 MOC3083	l _{FT}	_ _ _	_ _ _	15 10 5	mA
Peak On–State Voltage, Either Direction (I _{TM} = 100 mA, I _F = Rated I _{FT})	V _{TM}	_	1.8	3	Volts
Holding Current, Either Direction	lн	_	250	_	μΑ
Inhibit Voltage (MT1–MT2 Voltage above which device will not trigger) (IF = Rated IFT)	VINH	_	5	20	Volts
Leakage in Inhibited State (IF = Rated IFT, VDRM = 800 V, Off State)	I _{DRM2}	_	300	500	μА

- 1. Test voltage must be applied within dv/dt rating.
- 2. All devices are guaranteed to trigger at an I_F value less than or equal to max I_FT. Therefore, recommended operating I_F lies between max I_FT (15 mA for MOC3081, 10 mA for MOC3082, 5 mA for MOC3083) and absolute max I_F (60 mA).
- 3. This is static dv/dt. See Figure 7 for test circuit. Commutating dv/dt is a function of the load–driving thyristor(s) only.

TYPICAL CHARACTERISTICS





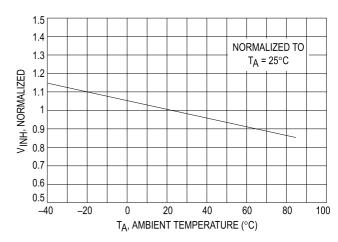


Figure 2. Inhibit Voltage versus Temperature



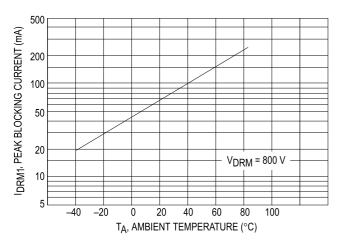


Figure 3. Leakage with LED Off versus Temperature

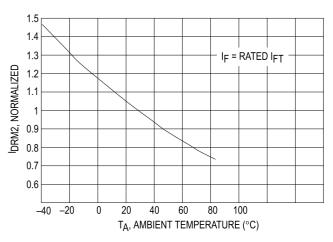


Figure 4. IDRM2, Leakage in Inhibit State versus Temperature

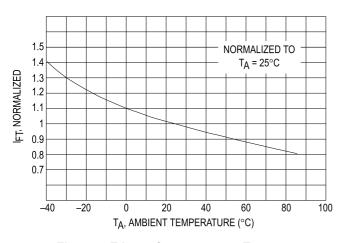


Figure 5. Trigger Current versus Temperature

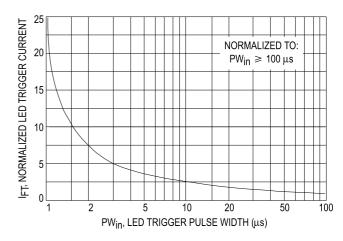
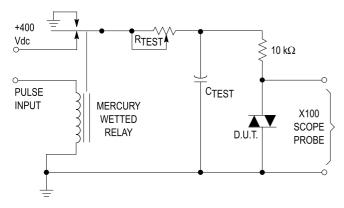


Figure 6. LED Current Required to Trigger versus LED Pulse Width



- The mercury wetted relay provides a high speed repeated pulse to the D.U.T.
- $2.\,\,100x\,scope\,probes\,are\,used, to\,allow\,high\,speeds\,and\,voltages.$
- 3. The worst–case condition for static dv/dt is established by triggering the D.U.T. with a normal LED input current, then removing the current. The variable R_{TEST} allows the dv/dt to be gradually increased until the D.U.T. continues to trigger in response to the applied voltage pulse, even after the LED current has been removed. The dv/dt is then decreased until the D.U.T. stops triggering. τ_{RC} is measured at this point and recorded.

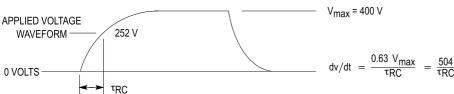
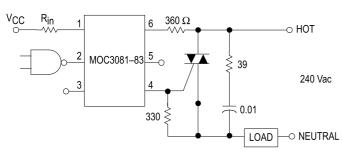


Figure 7. Static dv/dt Test Circuit





* For highly inductive loads (power factor < 0.5), change this value to 360 ohms.

Typical circuit for use when hot line switching is required. In this circuit the "hot" side of the line is switched and the load connected to the cold or neutral side. The load may be connected to either the neutral or hot line.

 $R_{\mbox{\scriptsize in}}$ is calculated so that IF is equal to the rated IFT of the part, 15 mA for the MOC3081, 10 mA for the MOC3082, and 5 mA for the MOC3083. The 39 ohm resistor and 0.01 μF capacitor are for snubbing of the triac and may or may not be necessary depending upon the particular triac and load used.

Figure 8. Hot-Line Switching Application Circuit

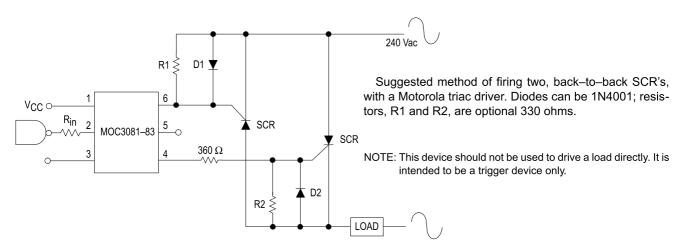
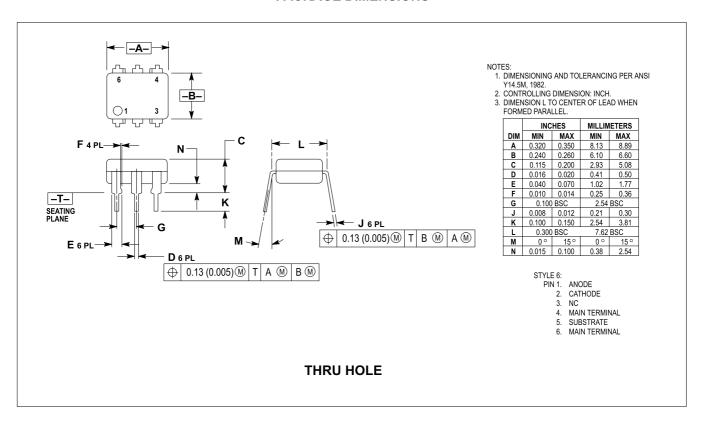
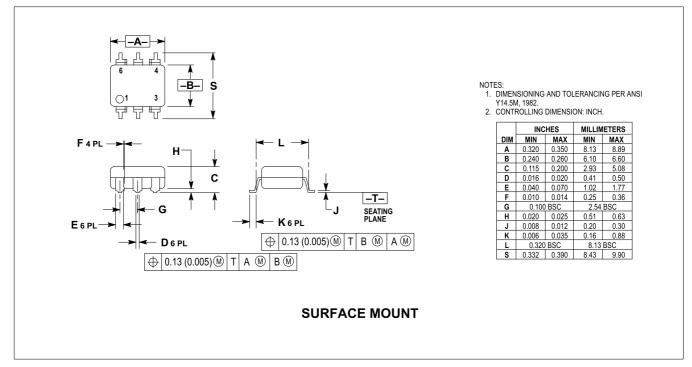


Figure 9. Inverse-Parallel SCR Driver Circuit

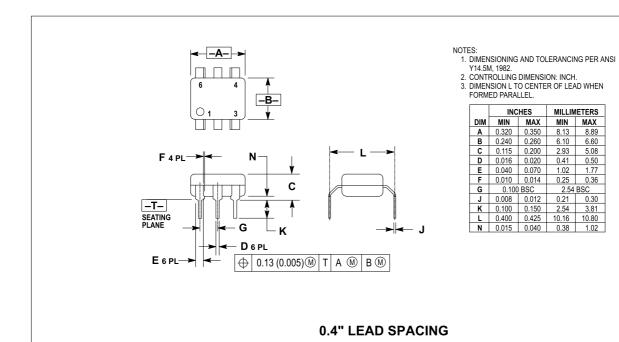


PACKAGE DIMENSIONS











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